


<b>Search Notes</b>  	<b>Application/Control No.</b>  10524444	<b>Applicant(s)/Patent Under Reexamination</b>  MOCHIZUKI ET AL.
	<b>Examiner</b>  HENOK G HEYI	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Searched EAST and referred to International Search Report (ISR). Some of the subclasses searched are 369/47.1, 53.1, 53.2, 53.41 and 59.1 (text search only - please see search history printout).	05/05/2008	Henok Heyi
Search updated.	11/06/2008	Henok Heyi
Updated search.	03/25/2009	Henok Heyi

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HENOK G HEYI/  
Examiner, Art Unit 2627